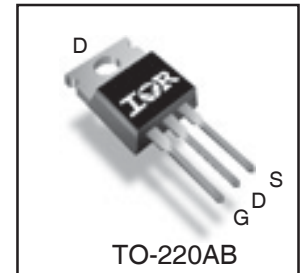
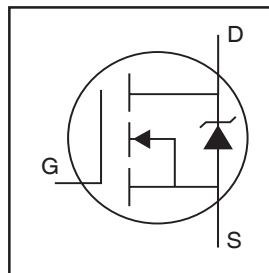


# IRFB4227PbF

## Features

- Advanced Process Technology
- Key Parameters Optimized for PDP Sustain, Energy Recovery and Pass Switch Applications
- Low  $E_{PULSE}$  Rating to Reduce Power Dissipation in PDP Sustain, Energy Recovery and Pass Switch Applications
- Low  $Q_G$  for Fast Response
- High Repetitive Peak Current Capability for Reliable Operation
- Short Fall & Rise Times for Fast Switching
- 175°C Operating Junction Temperature for Improved Ruggedness
- Repetitive Avalanche Capability for Robustness and Reliability
- Class-D Audio Amplifier 300W-500W (Half-bridge)

Key Parameters		
$V_{DS}$ max	200	V
$V_{DS}$ (Avalanche) typ.	240	V
$R_{DS(ON)}$ typ. @ 10V	19.7	mΩ
$I_{RP}$ max @ $T_C = 100^\circ\text{C}$	130	A
$T_J$ max	175	°C



G	D	S
Gate	Drain	Source

## Description

This HEXFET® Power MOSFET is specifically designed for Sustain; Energy Recovery & Pass switch applications in Plasma Display Panels. This MOSFET utilizes the latest processing techniques to achieve low on-resistance per silicon area and low  $E_{PULSE}$  rating. Additional features of this MOSFET are 175°C operating junction temperature and high repetitive peak current capability. These features combine to make this MOSFET a highly efficient, robust and reliable device for PDP driving applications.

## Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{GS}$	Gate-to-Source Voltage	±30	V
$I_D$ @ $T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V	65	A
$I_D$ @ $T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V	46	
$I_{DM}$	Pulsed Drain Current ①	260	
$I_{RP}$ @ $T_C = 100^\circ\text{C}$	Repetitive Peak Current ⑤	130	
$P_D$ @ $T_C = 25^\circ\text{C}$	Power Dissipation	330	W
$P_D$ @ $T_C = 100^\circ\text{C}$	Power Dissipation	190	
	Linear Derating Factor	2.2	W/°C
$T_J$	Operating Junction and	-40 to + 175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature for 10 seconds	300	
	Mounting Torque, 6-32 or M3 Screw	10lb·in (1.1N·m)	N

## Thermal Resistance

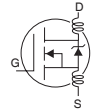
	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ④	—	0.45	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient ④	—	62	

Notes ① through ⑥ are on page 8

# IRFB4227PbF

## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	200	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	170	—	mV/°C	Reference to $25^\circ\text{C}, I_D = 1mA$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	19.7	24	mΩ	$V_{GS} = 10V, I_D = 46A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient	—	-13	—	mV/°C	
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	20	μA	$V_{DS} = 200V, V_{GS} = 0V$
		—	—	1.0	mA	$V_{DS} = 200V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{GS} = -20V$
$g_{fs}$	Forward Transconductance	49	—	—	S	$V_{DS} = 25V, I_D = 46A$
$Q_g$	Total Gate Charge	—	70	98	nC	$V_{DD} = 100V, I_D = 46A, V_{GS} = 10V$ ③
$Q_{gd}$	Gate-to-Drain Charge	—	23	—	nC	
$t_{d(on)}$	Turn-On Delay Time	—	33	—	ns	$V_{DD} = 100V$ $I_D = 46A$ $R_G = 2.5\Omega$ $V_{GS} = 10V$ ③
$t_r$	Rise Time	—	20	—		
$t_{d(off)}$	Turn-Off Delay Time	—	21	—		
$t_f$	Fall Time	—	31	—		
$t_{st}$	Shoot Through Blocking Time	100	—	—	ns	$V_{DD} = 160V, V_{GS} = 15V, R_G = 4.7\Omega$
$E_{PULSE}$	Energy per Pulse	—	570	—	μJ	$L = 220nH, C = 0.4\mu F, V_{GS} = 15V$ $V_{DS} = 160V, R_G = 4.7\Omega, T_J = 25^\circ\text{C}$
		—	910	—		$L = 220nH, C = 0.4\mu F, V_{GS} = 15V$ $V_{DS} = 160V, R_G = 4.7\Omega, T_J = 100^\circ\text{C}$
$C_{iss}$	Input Capacitance	—	4600	—	pF	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1.0MHz,$ $V_{GS} = 0V, V_{DS} = 0V$ to 160V
$C_{oss}$	Output Capacitance	—	460	—		
$C_{riss}$	Reverse Transfer Capacitance	—	91	—		
$C_{oss\ eff.}$	Effective Output Capacitance	—	360	—		
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		

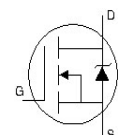


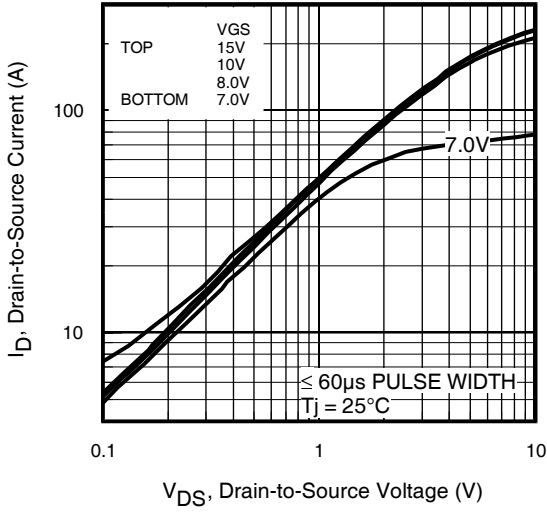
## Avalanche Characteristics

	Parameter	Typ.	Max.	Units
$E_{AS}$	Single Pulse Avalanche Energy ②	—	140	mJ
$E_{AR}$	Repetitive Avalanche Energy ①	—	33	mJ
$V_{DS(Avalanche)}$	Repetitive Avalanche Voltage ①	240	—	V
$I_{AS}$	Avalanche Current ②	—	39	A

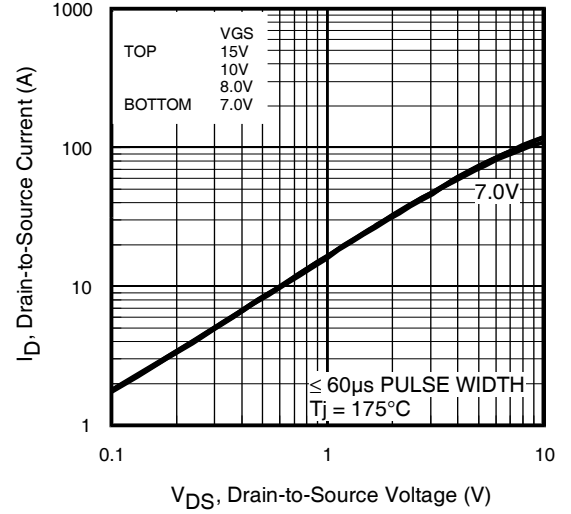
## Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S @ T_C = 25^\circ\text{C}$	Continuous Source Current (Body Diode)	—	—	65	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	260		
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 46A, V_{GS} = 0V$ ③
$t_{rr}$	Reverse Recovery Time	—	100	150	ns	$T_J = 25^\circ\text{C}, I_F = 46A, V_{DD} = 50V$
$Q_{rr}$	Reverse Recovery Charge	—	430	640	nC	$di/dt = 100A/\mu s$ ③

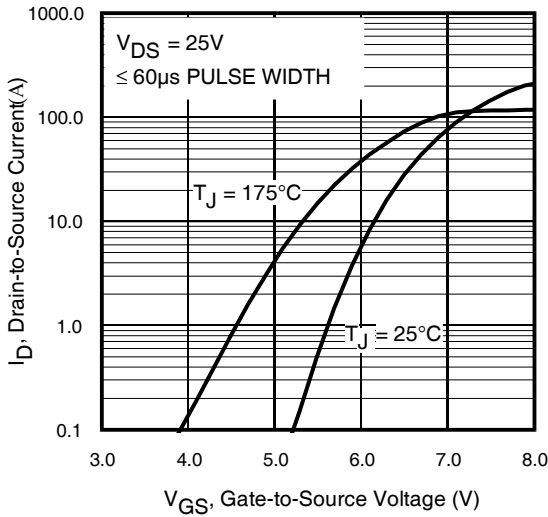




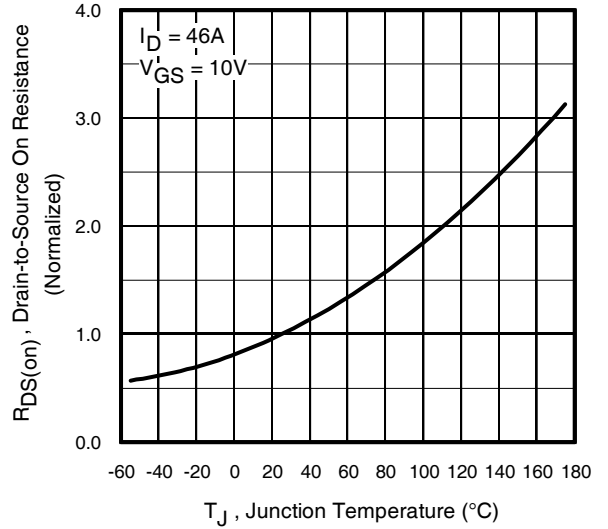
**Fig 1.** Typical Output Characteristics



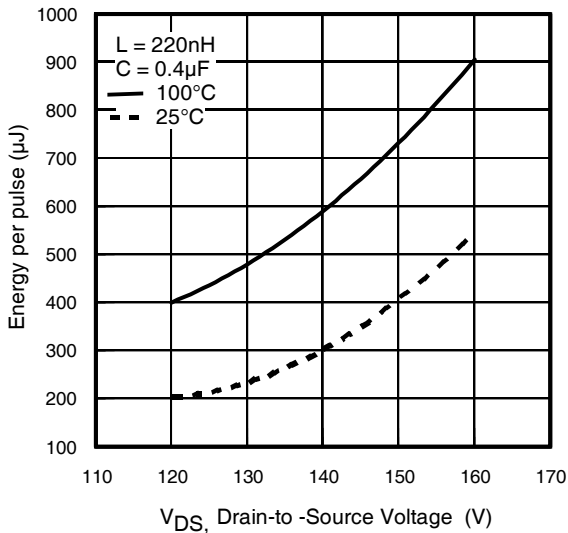
**Fig 2.** Typical Output Characteristics



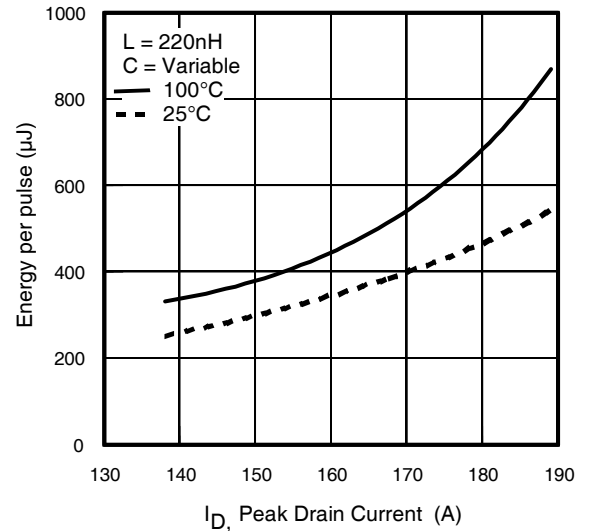
**Fig 3.** Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance vs. Temperature

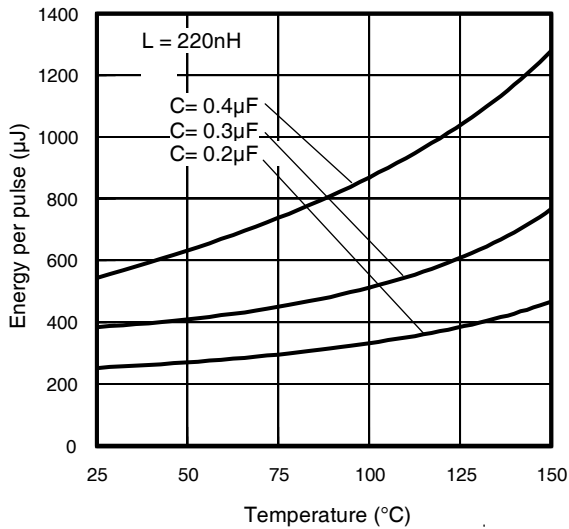


**Fig 5.** Typical  $E_{PULSE}$  vs. Drain-to-Source Voltage

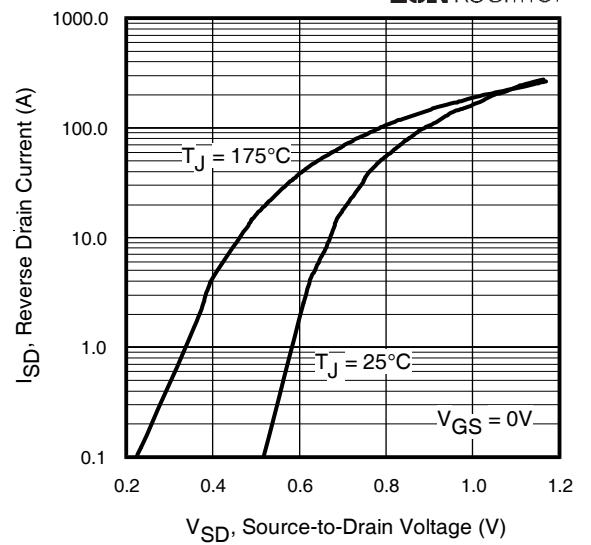


**Fig 6.** Typical  $E_{PULSE}$  vs. Drain Current

# IRFB4227PbF



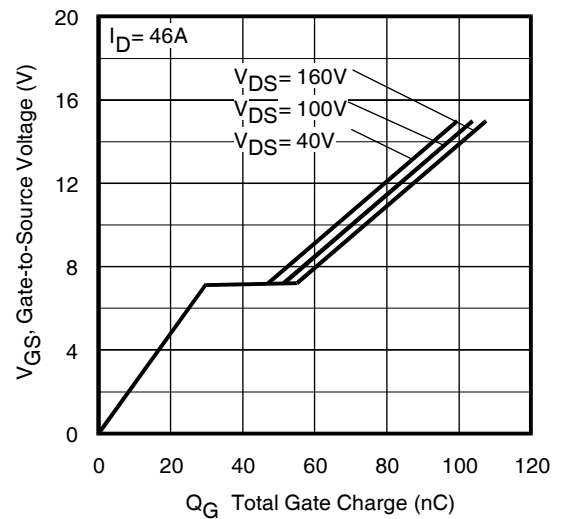
**Fig 7.** Typical  $E_{\text{PULSE}}$  vs. Temperature



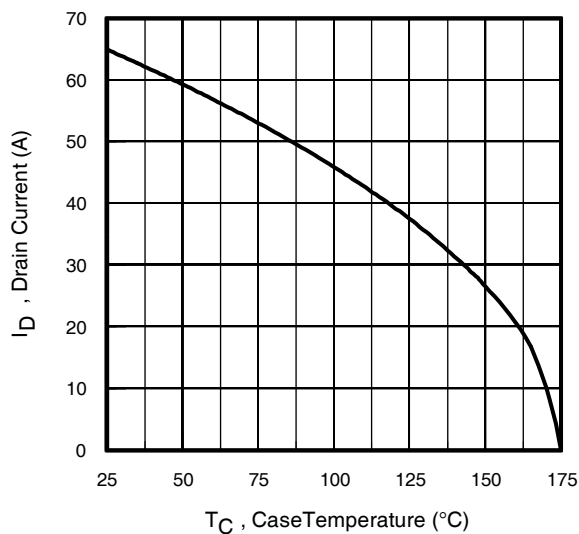
**Fig 8.** Typical Source-Drain Diode Forward Voltage



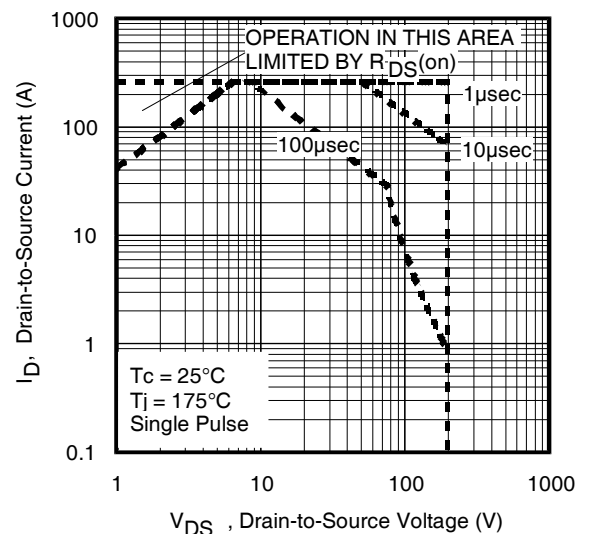
**Fig 9.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 10.** Typical Gate Charge vs. Gate-to-Source Voltage



**Fig 11.** Maximum Drain Current vs. Case Temperature



**Fig 12.** Maximum Safe Operating Area

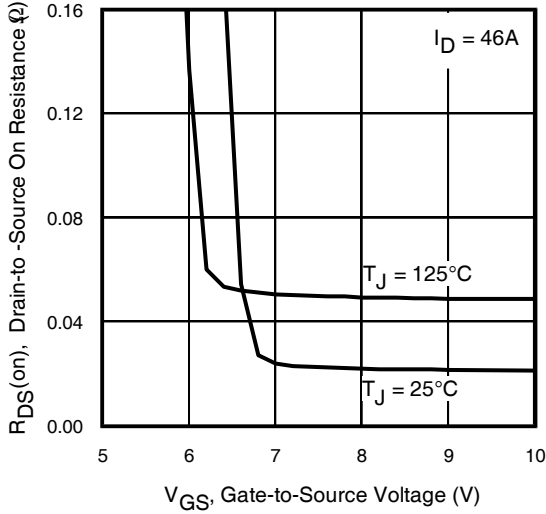


Fig 13. On-Resistance Vs. Gate Voltage

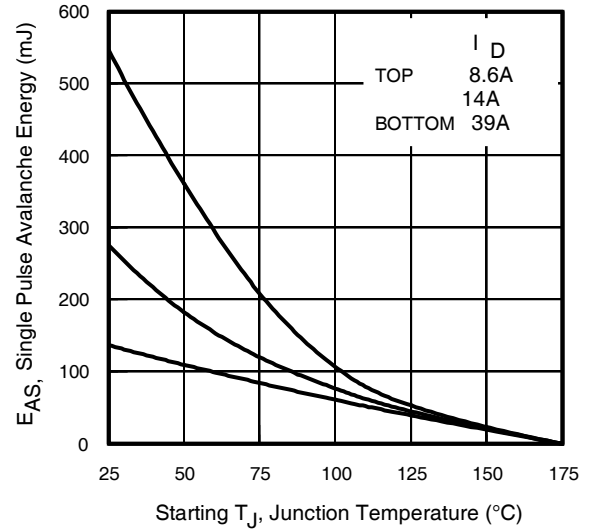


Fig 14. Maximum Avalanche Energy Vs. Temperature

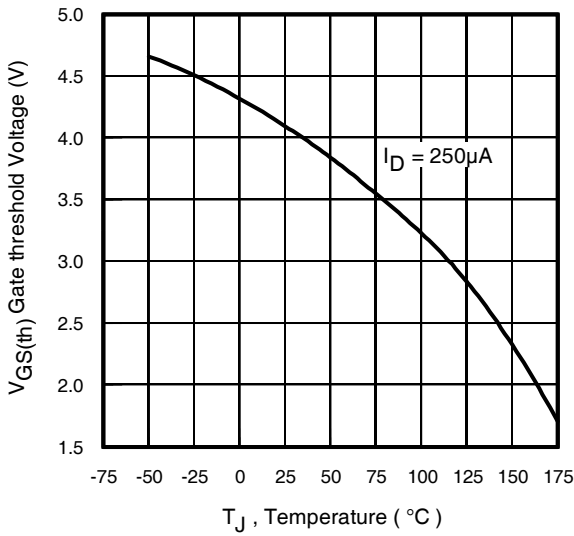


Fig 15. Threshold Voltage vs. Temperature

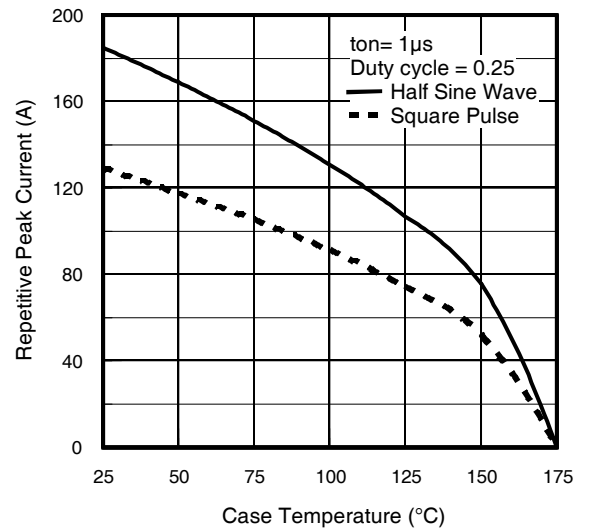


Fig 16. Typical Repetitive peak Current vs. Case temperature

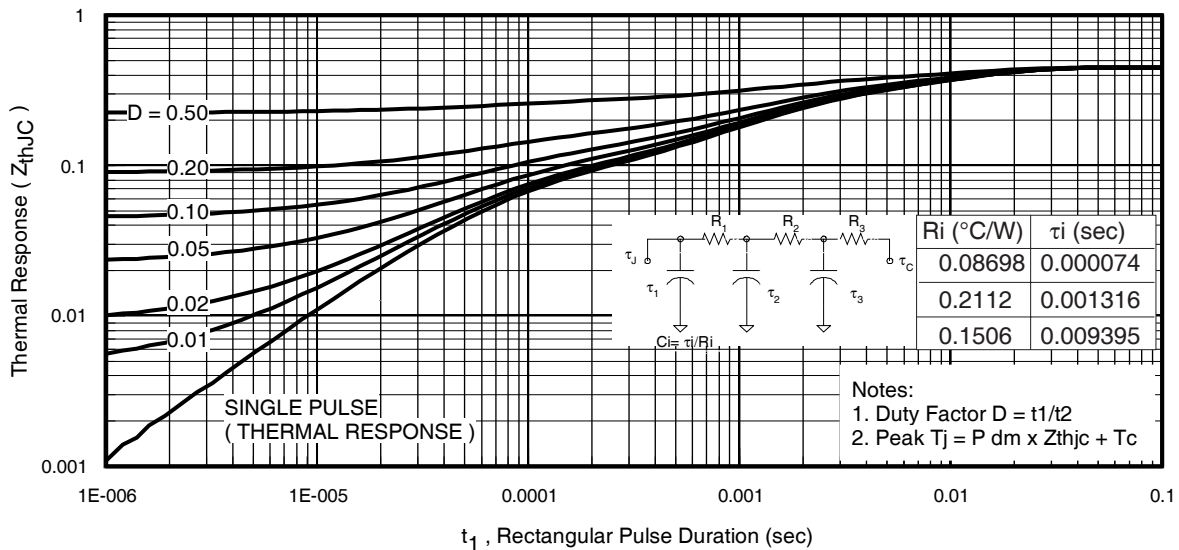
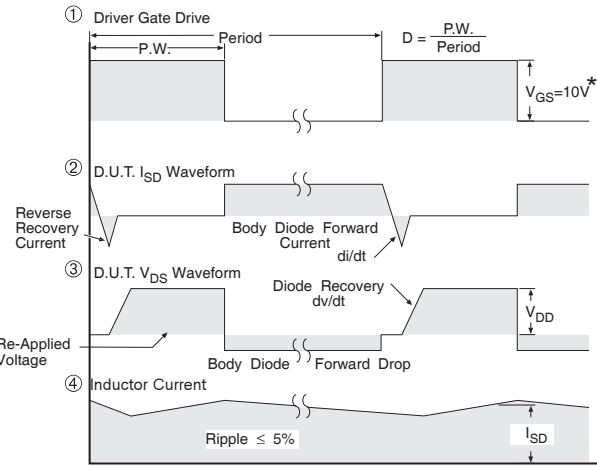
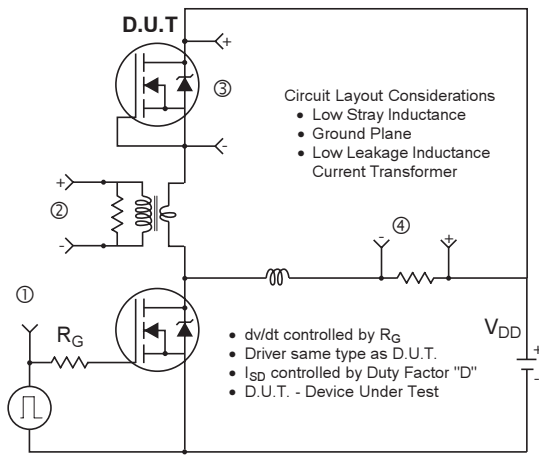
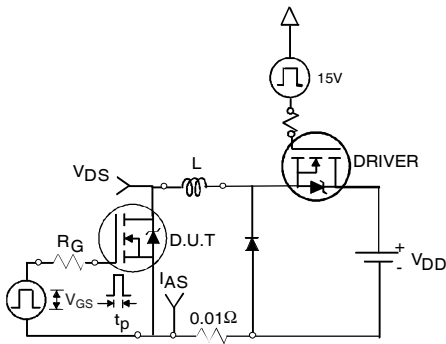


Fig 17. Maximum Effective Transient Thermal Impedance, Junction-to-Case

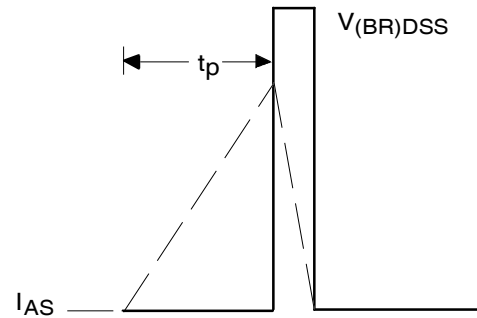


\*  $V_{GS} = 5V$  for Logic Level Devices

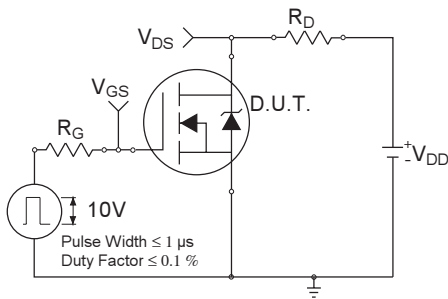
**Fig 18. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs**



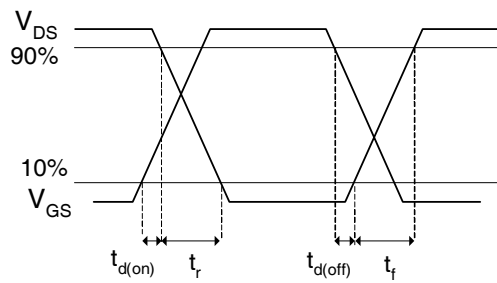
**Fig 19a. Unclamped Inductive Test Circuit**



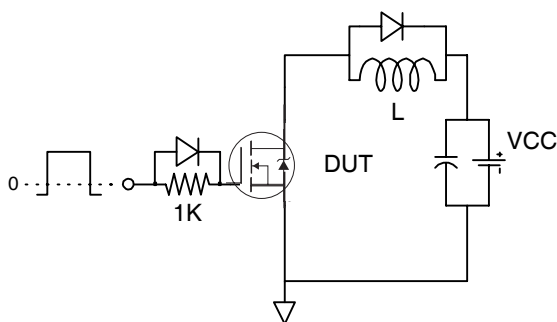
**Fig 19b. Unclamped Inductive Waveforms**



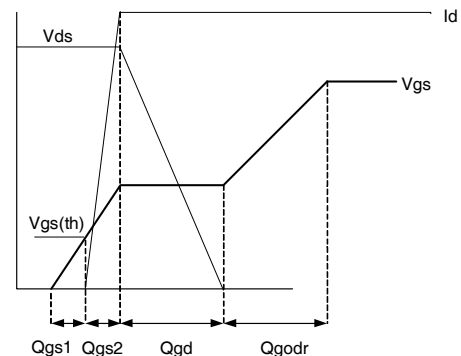
**Fig 20a. Switching Time Test Circuit**



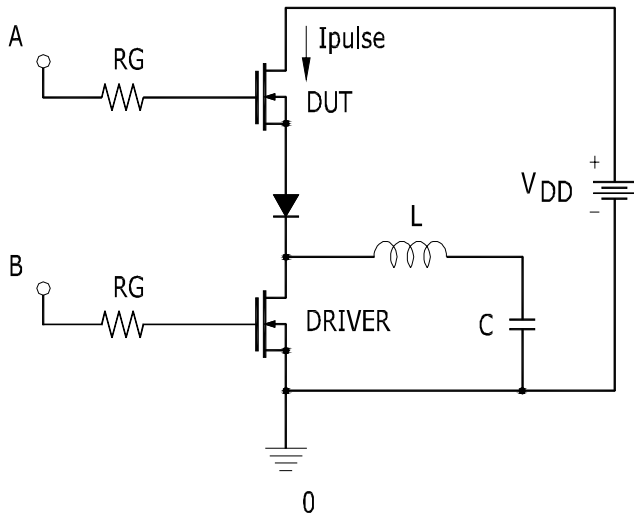
**Fig 20b. Switching Time Waveforms**



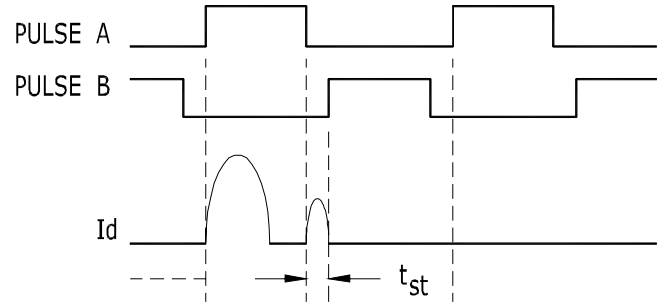
**Fig 21a. Gate Charge Test Circuit**



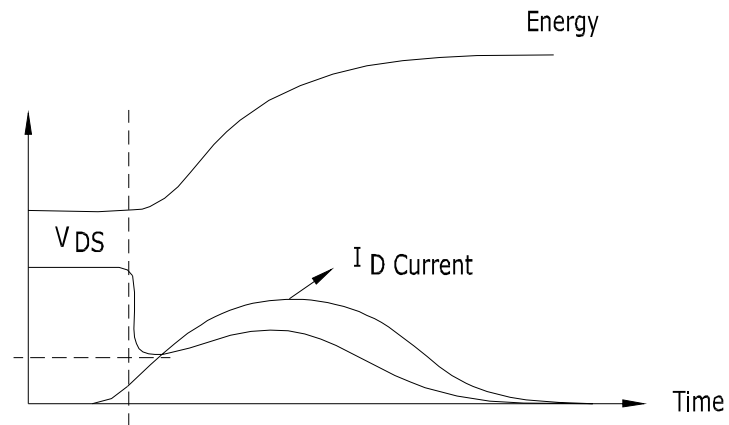
**Fig 21b. Gate Charge Waveform**



**Fig 21a.**  $t_{st}$  and  $E_{PULSE}$  Test Circuit



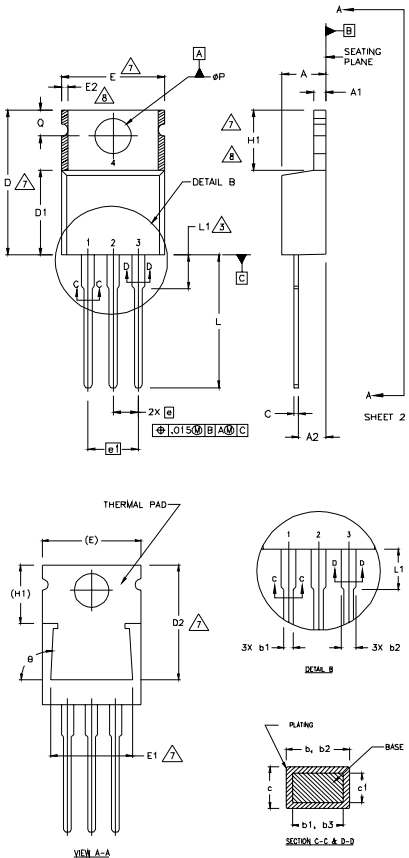
**Fig 21b.**  $t_{st}$  Test Waveforms



**Fig 21c.**  $E_{PULSE}$  Test Waveforms

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## TO-220AB Package Outline (Dimensions are shown in millimeters (inches))



**NOTES:**

- 1 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- 2 DIMENSIONS ARE SHOWN IN INCHES (MILLIMETERS).
- 3 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
- 4 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5 DIMENSION b1 & c1 APPLY TO BASE METAL ONLY.
- 6 CONTROLLING DIMENSION : INCHES.
- 7 THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- 8 DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.

**LEAD ASSIGNMENTS**

**HEXFET**  
1.- GATE  
2.- DRAIN  
3.- SOURCE

**IGBTs, CoPACK**

1.- GATE  
2.- COLLECTOR  
3.- EMITTER

**DIODES**

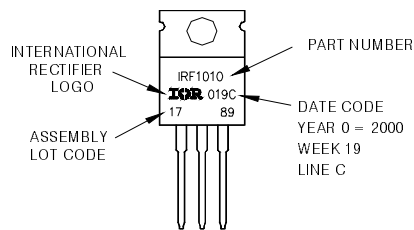
1.- ANODE/OPEN  
2.- CATHODE  
3.- ANODE

SYMBOL	DIMENSIONS				NOTES
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	3.56	4.82	.140	.190	
A1	0.51	1.40	.020	.055	
A2	2.04	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.96	.015	.038	5
b2	1.15	1.77	.045	.070	
b3	1.15	1.73	.045	.068	
c	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	12.19	12.88	.480	.507	7
E	9.66	10.66	.380	.420	4,7
E1	8.38	8.89	.330	.350	7
e	2.54 BSC		.100 BSC		
e1	5.08		.200 BSC		
H1	5.85	6.55	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	-	6.35	-	.250	3
øP	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	
ø	9.0°-9.3°		9.0°-9.3°		

## TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010  
LOT CODE 1789  
ASSEMBLED ON WW 19, 2000  
IN THE ASSEMBLY LINE 'C'

Note: 'P' in assembly line position  
indicates 'Lead - Free'



TO-220AB packages are not recommended for Surface Mount Application.

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.18\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 39\text{A}$ .
- ③ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④  $R_{\theta}$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .
- ⑤ Half sine wave with duty cycle = 0.25,  $t_{on} = 1\mu\text{sec}$ .

**Note:** For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Industrial market.  
Qualification Standards can be found on IR's Web site.